

STS15N4LL

N-channel 40V - 0.0042Ω - 15A - SO-8 STripFET™ Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STS15N4LL	40V	<0.005Ω	15A

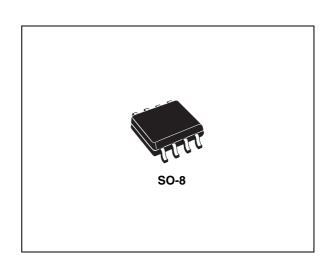
- Optimal R_{DS(on)}x Q_g trade-off @ 4.5V
- Conduction losses reduced
- Switching losses reduced

Description

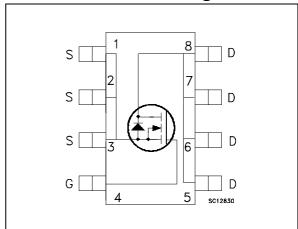
This N-channel enhancement mode Power MOSFET is the latest refinement of STMicroelectronic unique "Single Feature Size™" strip-based process with less critical aligment steps and therefore a remarkable manufacturing reproducibility. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and low gate charge.

Applications

■ Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STS15N4LL	15N4LL-	SO-8	Tape & reel

Contents STS15N4LL

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STS15N4LL Electrical ratings

1 Electrical ratings

Table 1. Absolute maximim ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	40	V
V _{GS}	Gate-source voltage	± 16	V
V _{GS} ⁽¹⁾	Gate- source voltage	±18	V
I _D	Drain current (continuous) at T _C = 25°C	15	Α
I _D	Drain current (continuous) at T _C = 100°C	9.3	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	60	Α
P _{TOT}	Total dissipation at T _C = 25°C	2.7	W
E _{AS} (3)	Single pulse avalanche energy	2	J

^{1.} Guaranteed for test time ≤ 15ms

Table 2. Thermal resistance

Symbol	Parameter	Value	Unit
R _{thj} -pcb ⁽¹⁾	Thermal resistance junction-PCB Max	47	°C/W
T _I	Maximum lead temperature for soldering	-55 to 150	°C
T _{stg}	Storage temperature	-55 to 150	°C

^{1.} When mounted of FR-4 board with 1 inch² pad, 2oz of Cu and t< 10sec

^{2.} Pulse width limited by Tjmax

^{3.} Starting $T_j = 25$ °C, $I_D = 7.5$ A, $V_{DD} = 25$ V

Electrical characteristics STS15N4LL

2 Electrical characteristics

 $(T_J = 25 \, ^{\circ}C \text{ unless otherwise specified})$

Table 3. On/off states

Symbol	Parameter	Parameter Test conditions		Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0$	40			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = max rating, V _{DS} =max rating @ 125°C			10 100	μ Α μ Α
I _{GSS}	Gate body leakage Current (V _{DS} = 0)	$V_{GS} = \pm 16V$			±200	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1			V
R _{DS(on)}	Static drain-source On resistance	V_{GS} = 10V, I_{D} = 7.5A V_{GS} = 4.5V, I_{D} = 7.5A		0.0042 0.005	0.005 0.007	Ω

Table 4. Dynamic

	- y					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer Capacitance	$V_{DS} = 25V$, f=1 MHz, $V_{GS} = 0$		2530 574 29		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 20V, I_{D} = 15A V_{GS} = 4.5V (see Figure 13)		21.5 6.9 8.2	28	nC nC nC
R_{G}	Gate input resistance	f=1 MHz Gate DC Bias = 0 Test signal level = 20mV open drain	1	3	5	Ω

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	V_{DD} = 20V, I_D = 7.5A, R_G = 4.7 Ω , V_{GS} = 10V (see Figure 12)		17 25		ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	V_{DD} = 20V, I_D = 7.5A, R_G = 4.7 Ω , V_{GS} = 10V (see Figure 12)		62 9		ns ns

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current				15	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				60	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 15A, V _{GS} = 0			1.2	V
t _{rr}	Reverse recovery time	$I_{SD} = 15A, V_{DD} = 30V,$		43		ns
Q_{rr}	Reverse recovery charge	di/dt = 100A/μs,		64		nC
I _{RRM}	Reverse recovery current	Tj = 150°C (see Figure 17)		3		Α

- 1. Pulse width limited by safe operating area
- 2. Pulsed: pulse duration = $300\mu s$, duty cycle 1.5%

Electrical characteristics STS15N4LL

Electrical characteristics (curves) 2.1

Figure 1. Safe operating area

Figure 2. Thermal impedance

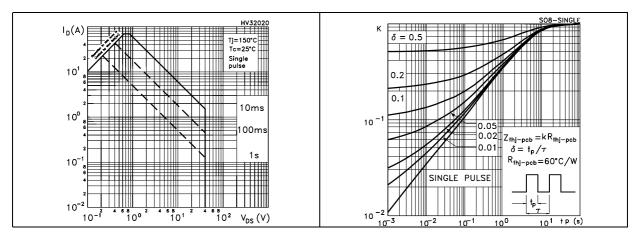
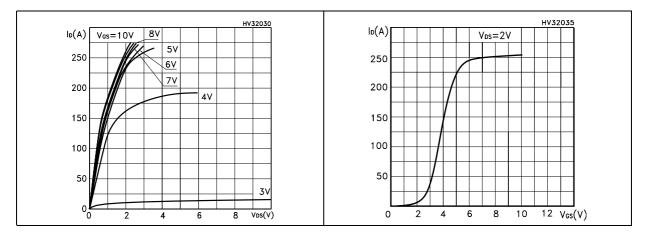


Figure 3. **Output characterisics**

Figure 4. **Transfer characteristics**



Normalized B_{VDSS} vs temperature Figure 6.

100

150 TJ(°C)

 $R_{DS(on)}$ (Ω) $V_{GS} = 10V$ 4.3 4.1 4.0 L I_D(A)

Static drain-source on resistance

V(BR)DSS

(norm

1.1

1.0

0.5

√6s=0

In=250µA

Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

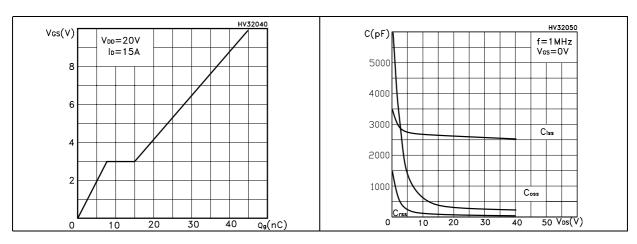


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

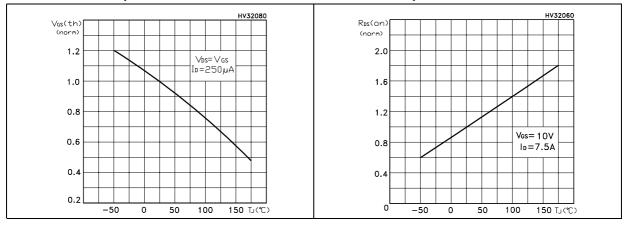
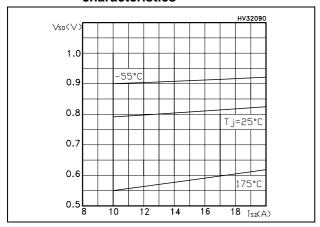


Figure 11. Source-drain diode forward characteristics



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Test circuit STS15N4LL

3 Test circuit

Figure 12. Switching times test circuit for resistive load

Figure 13. Gate charge test circuit

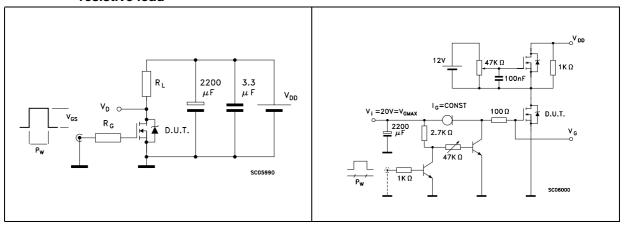


Figure 14. Test circuit for inductive load switching and diode recovery times

Figure 15. Unclamped Inductive load test circuit

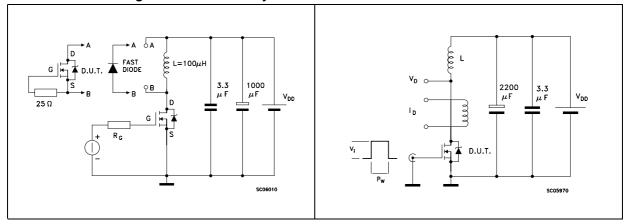
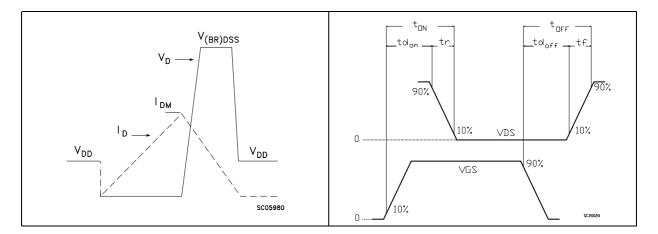


Figure 16. Unclamped inductive waveform

Figure 17. Switching time waveform



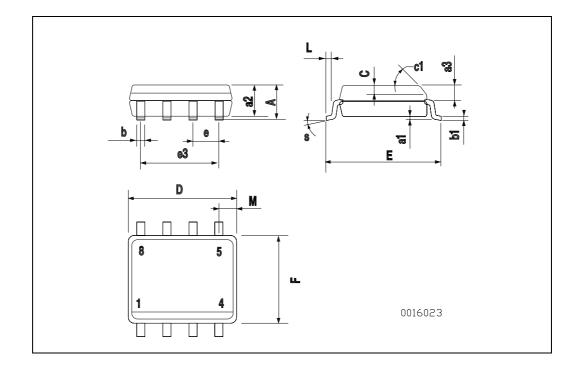
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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available atwww.st.com

SO-8 MECHANICAL DATA

DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1			45	(typ.)		•
D	4.8		5.0	0.188		0.196
Е	5.8		6.2	0.228		0.244
е		1.27			0.050	
еЗ		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
М			0.6			0.023
S		•	8 (r	nax.)	•	•



STS15N4LL Revision history

5 Revision history

Table 7. Revision history

Date	Revision	Changes
06-Jun-2006	1	First release

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